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Issued date : August 25, 2017 FCC ID : T8VCL6-904

RADIO TEST REPORT

Test Report No.: 11766059H-A-R2

Applicant : ASAHI DENSO CO., LTD.

Type of Equipment : SMART KEY

Model No. : CL6-904

Test regulation : FCC Part 15 Subpart C: 2017

FCC ID : T8VCL6-904

Test Result : Complied

1. This test report shall not be reproduced in full or partial, without the written approval of UL Japan, Inc.

- 2. The results in this report apply only to the sample tested.
- 3. This sample tested is in compliance with above regulation.
- 4. The test results in this report are traceable to the national or international standards.
- 5. This test report must not be used by the customer to claim product certification, approval, or endorsement by NVLAP, NIST, or any agency of the Federal Government.
- 6. This test report covers Radio technical requirements. It does not cover administrative issues such as Manual or non-Radio test related Requirements. (if applicable)
- 7. This report is a revised version of 11766059H-A-R1.

Date of test:

Representative test engineer:

May 27 to August 22, 2017

Ken Fujita Engineer

Consumer Technology Division

Approved by:

Motoya Imura Engineer

Consumer Technology Division



NVLAP LAB CODE: 200572-0

This laboratory is accredited by the NVLAP LAB CODE 200572-0, U.S.A. The tests reported herein have been performed in accordance with its terms of accreditation. *As for the range of Accreditation in NVLAP, you may refer to the WEB address,

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REVISION HISTORY

Original Test Report No.: 11766059H-A

Test report No. 11766059H-A 11766059H-A-R1 11766059H-A-R1 11766059H-A-R2 11766059H-A-R2	Date July 25, 2017 August 22, 2017 August 22, 2017 August 22, 2017 August 25, 2017 August 25, 2017	Page revised - P.5 P.9 P.12, 13	Contents - Correction of Worst margin for Electric Field Strength of Spurious Emission in Clause 3.2 Correction of Measurement range in SECTION 5 Correction of data for Radiated Emission
11766059H-A-R1 11766059H-A-R1 11766059H-A-R1	August 22, 2017 August 22, 2017 August 22, 2017 August 25, 2017	P.9	Field Strength of Spurious Emission in Clause 3.2 Correction of Measurement range in SECTION 5
11766059H-A-R1 11766059H-A-R1 11766059H-A-R2	August 22, 2017 August 22, 2017 August 25, 2017	P.9	Field Strength of Spurious Emission in Clause 3.2 Correction of Measurement range in SECTION 5
11766059H-A-R1 11766059H-A-R2	August 22, 2017 August 25, 2017		Correction of Measurement range in SECTION 5
11766059H-A-R2	August 25, 2017	P.12, 13	Correction of data for Radiated Emission
	August 25, 2017 August 25, 2017		test
11766059H-A-R2	August 25, 2017	P.12	Deletion of calculation under the data
		P.13	Correction of plot data

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Facsimile : +81 596 24 8124

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SECTION 1: Customer information

Company Name : ASAHI DENSO CO., LTD.

Address : 6-2-1 Somejidai, Hamakita-ku, Hamamatsu, Shizuoka 434-0046, Japan

Telephone Number : +81-53-586-7383 Facsimile Number : +81-53-584-1589 Contact Person : Tomohiro Yaguchi

SECTION 2: Equipment under test (E.U.T.)

2.1 Identification of E.U.T.

Type of Equipment : SMART KEY Model No. : CL6-904

Serial No. : Refer to Clause 4.2

Rating : DC 3.0 V Receipt Date of Sample : May 23, 2017

Country of Manufacture : Japan

Condition of EUT : Production prototype

(Not for Sale: This sample is equivalent to mass-produced items.)

Modification of EUT : No Modification by the test lab

2.2 Product Description

Model No: CL6-904 (referred to as the EUT in this report) is the SMART KEY.

General Specification

Clock frequencies in the system : 5 MHz

Radio Specification

Radio Type : Transceiver
Frequency of Operation : 433.92 MHz
Modulation : FSK
Method of Frequency Generation : Crystal

Operating temperature range : -20 deg. C to +65 deg. C

Radio Type : Receiver Frequency of Operation : 134.2 kHz *1)

*1) The test of receiver part was performed separately from this test report, and the conformability is confirmed.

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SECTION 3: Test specification, procedures & results

3.1 Test Specification

Test Specification : FCC Part 15 Subpart C

FCC Part 15 final revised on June 14, 2017 and effective July 14, 2017

Title : FCC 47CFR Part15 Radio Frequency Device Subpart C Intentional Radiators

Section 15.231 Periodic operation in the band 40.66 - 40.70MHz

and above 70MHz

3.2 Procedures and results

Item	Test Procedure	Specification	Worst margin	Results	Remarks
Conducted emission	FCC: ANSI C63.10:2013 6 Standard test methods IC: RSS-Gen 8.8	FCC: Section 15.207 IC: RSS-Gen 8.8	-N/A	N/A*1)	-
Automatically Deactivate	FCC: ANSI C63.10:2013 6 Standard test methods	FCC: Section 15.231(a)(1) IC: RSS-210 A1.1	N/A	Complied	Radiated
Electric Field Strength of Fundamental Emission	FCC: ANSI C63.10:2013 6 Standard test methods IC: RSS-Gen 6.12	FCC: Section 15.231(b) IC: RSS-210 A1.2	3.2 dB Vertical PK with Duty factor	Complied	Radiated
Electric Field Strength of Spurious Emission	FCC: ANSI C63.10:2013 6 Standard test methods IC: RSS-Gen 6.13	FCC: Section 15.205 Section 15.209 Section 15.231(b) IC: RSS-210 A1.2, 4.4 RSS-Gen 8.9	2.0 dB 4339.200 MHz -Vertical PK with Duty factor	Complied	Radiated
-20dB Bandwidth	FCC: ANSI C63.10:2013 6 Standard test methods IC: -	FCC: Section 15.231(c) IC: Reference data	N/A	Complied	Radiated

Note: UL Japan, Inc.'s EMI Work Procedures No. 13-EM-W0420 and 13-EM-W0422.

FCC 15.31 (e)

This test was performed with the New Battery (DC 3.0 V) during the tests. Therefore, the EUT complies with the requirement.

FCC Part 15.203 Antenna requirement

It is impossible for end users to replace the antenna, because the antenna is mounted inside of the EUT. Therefore, the equipment complies with the antenna requirement of Section 15.203.

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^{*} The revision on June 14, 2017, does not affect the test specification applied to the EUT.

^{*} Also the EUT complies with FCC Part 15 Subpart B.

^{*1)} The test is not applicable since the EUT does not have AC Mains.

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3.3 Addition to standard

Item	Test Procedure	Specification	Worst margin	Results	Remarks
99 % Occupied Bandwidth	IC: RSS-Gen 6.6	IC: RSS-210 A1.1.3	N/A	Complied	Radiated

Other than above, no addition, exclusion nor deviation has been made from the standard.

3.4 Uncertainty

EMI

The following uncertainties have been calculated to provide a confidence level of 95 % using a coverage factor k = 2.

	Radiated emission (Below 1 GHz)				
Polarity	(3 m*	(3 m*)(+/-) (10 m*))(+/-)	
Folarity	30 MHz -	200 MHz -	30 MHz -	200 MHz -	
	200 MHz	1000 MHz	200 MHz	1000 MHz	
Horizontal	5.0 dB	5.3 dB	5.0 dB	5.0 dB	
Vertical	4.7 dB	5.9 dB	5.0 dB	5.1 dB	

Radiated emission (Above 1 GHz)						
(3 m*)(+/-) (1 m*)(+/-) (10 m*)(+/-)						
1 GHz - 6 GHz	6 GHz - 18 GHz	10 GHz - 26.5 GHz -		1 GHz -18 GHz		
		26.5 GHz	40 GHz			
5.2 dB	5.4 dB	5.5 dB	5.5 dB	5.4 dB		

^{*} Measurement distance

Radiated emission test(3 m)

The data listed in this report meets the limits unless the uncertainty is taken into consideration.

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3.5 Test Location

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Telephone: +81 596 24 8999 Facsimile: +81 596 24 8124

Telephone : 181 370 2-	IC Registration	Width x Depth x	Size of	Other
	Number	Height (m)	reference ground plane (m) / horizontal conducting plane	rooms
No.1 semi-anechoic chamber	2973C-1	19.2 x 11.2 x 7.7m	7.0 x 6.0m	No.1 Power source room
No.2 semi-anechoic chamber	2973C-2	7.5 x 5.8 x 5.2m	4.0 x 4.0m	-
No.3 semi-anechoic chamber	2973C-3	12.0 x 8.5 x 5.9m	6.8 x 5.75m	No.3 Preparation room
No.3 shielded room	-	4.0 x 6.0 x 2.7m	N/A	-
No.4 semi-anechoic chamber	2973C-4	12.0 x 8.5 x 5.9m	6.8 x 5.75m	No.4 Preparation room
No.4 shielded room	-	4.0 x 6.0 x 2.7m	N/A	-
No.5 semi-anechoic chamber	-	6.0 x 6.0 x 3.9m	6.0 x 6.0m	-
No.6 shielded room	-	4.0 x 4.5 x 2.7m	4.0 x 4.5 m	-
No.6 measurement room	-	4.75 x 5.4 x 3.0m	4.75 x 4.15 m	-
No.7 shielded room	-	4.7 x 7.5 x 2.7m	4.7 x 7.5m	-
No.8 measurement room	-	3.1 x 5.0 x 2.7m	N/A	-
No.9 measurement room	-	8.0 x 4.6 x 2.8m	2.4 x 2.4m	-
No.11 measurement room	-	6.2 x 4.7 x 3.0m	4.8 x 4.6m	-

^{*} Size of vertical conducting plane (for Conducted Emission test): 2.0 x 2.0m for No.1, No.2, No.3, and No.4 semi-anechoic chambers and No.3 and No.4 shielded rooms.

3.6 Test data, Test instruments, and Test set up.

Refer to APPENDIX.

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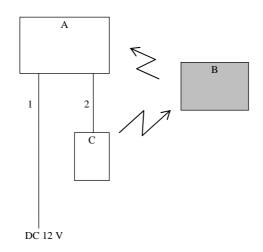
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SECTION 4: Operation of E.U.T. during testing

4.1 Operating Modes

Test Item	Mode			
Automatically Deactivate	Normal use mode, 433.92 MHz			
Electric Field Strength of Fundamental Emission	Transmitting mode (Tx), 433.92 MHz			
Electric Field Strength of Spurious Emission				
-20dB & 99% Occupied Bandwidth				
* The system was configured in typical fashion (as a customer would normally use it) for testing.				

4.2 Configuration and peripherals



^{*} Cabling and setup were taken into consideration and test data was taken under worse case conditions.

Description of EUT and Support equipment

No.	Item	Model number	Serial number	Manufacturer	Remarks
Α	HF Unit	CL8	No.1	ASAHI DENSO CO., LTD.	*1)
В	SMART KEY	CL6-904	No.1 *1)	ASAHI DENSO CO., LTD.	EUT
			No.2 *2)		
С	LF Antenna	CZ162	7510	ASAHI DENSO CO., LTD.	*1)

^{*1)} Used for Normal use mode only.

List of cables used

No.	Name	Length (m)	Shi	Remark	
			Cable	Connector	
1	DC Cable	1.0	Unshielded	Unshielded	*1)
2	Signal Cable	0.6	Unshielded	Unshielded	*1)

^{*1)} Used for Normal use mode only.

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^{*2)} Used for Transmitting mode only.

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SECTION 5: Radiated emission (Electric Field Strength of Fundamental and Spurious Emission)

Test Procedure and conditions

[For below 1GHz]

EUT was placed on a urethane platform of nominal size, 0.5 m by 1.0 m, raised 0.8 m above the conducting ground plane. The Radiated Electric Field Strength has been measured in a Semi Anechoic Chamber with a ground plane.

[For above 1GHz]

EUT was placed on a urethane platform of nominal size, 0.5 m by 0.5 m, raised 1.5 m above the conducting ground plane. The Radiated Electric Field Strength has been measured in a Semi Anechoic Chamber with absorbent materials lined on a ground plane.

Test was made with the antenna positioned in both the horizontal and vertical planes of polarization. The measurement antenna was varied in height above the conducting ground plane to obtain the maximum signal strength. Photographs of the set up are shown in Appendix 3.

[Transmitting mode] (Below 30 MHz)

The noise level was checked by moving a search-coil (Loop Antenna) close to the EUT.

(Above 30 MHz)

The Radiated Electric Field Strength has been measured on Semi anechoic chamber with a ground plane and at a distance of 3 m.

The measuring antenna height was varied between 1 and 4 m and EUT was rotated a full revolution in order to obtain the maximum value of the electric field strength.

The measurements were performed for both vertical and horizontal antenna polarization.

The radiated emission measurements were made with the following detector function of the test receiver / spectrum analyzer.

Test Antennas are used as below;

Frequency	Below 30 MHz	30 MHz to 200 MHz	200 MHz to 1 GHz	Above 1 GHz
Antenna Type	Loop	Biconical	Logperiodic	Horn

	From 9 kHz to 90 kHz and From 110 kHz to 150 kHz	From 90 kHz to 110 kHz	From 150 kHz to 490 kHz	From 490 kHz to 30 MHz	From 30 MHz to 1 GHz	Above 1 GHz
Detector Type	Peak	Peak	Peak	Peak	Peak and Peak with Duty factor	Peak and Peak with Duty factor
IF Bandwidth	200 Hz	200 Hz	9.1 kHz	9.1 kHz	120 kHz	PK: S/A: RBW 1 MHz, VBW: 3 MHz

⁻ The carrier level (or, noise levels) was (or were) measured at each position of all three axes X, Y and Z, and the position that has the maximum noise was determined.

Noise levels of all the frequencies were measured at the position.

- This EUT has two modes which mechanical key is folded in or out. The worst case was confirmed that mechanical key is folded in or out, as a result, the test which mechanical key was folded in was the worst case. Therefore the test was performed under the worst condition.

Measurement range : 9 kHz - 4.4 GHz
Test data : APPENDIX
Test result : Pass

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^{*}The result is rounded off to the second decimal place, so some differences might be observed.

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SECTION 6: Automatically deactivate

Test Procedure

The measurement was performed with Electric field strength using a spectrum analyzer.

Test data : APPENDIX

Test result : Pass

SECTION 7: -20 dB and 99 % Occupied Bandwidth

Test Procedure

The test was measured with a spectrum analyzer using a test fixture.

Test	Span	RBW	VBW	Sweep	Detector	Trace	Instrument used		
20 dB Bandwidth	150 kHz	1.5 kHz	5.1 kHz	Auto	Peak	Max Hold	Spectrum Analyzer		
99 % Occupied Bandwidth	Enough width to display emission skirts	1 to 5 % of OBW	Three times of RBW	Auto	Peak	Max Hold	Spectrum Analyzer		
Peak hold was appli	Peak hold was applied as Worst-case measurement.								

Test data : APPENDIX

Test result : Pass

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APPENDIX 1: Test data

Automatically deactivate 433.92 MHz

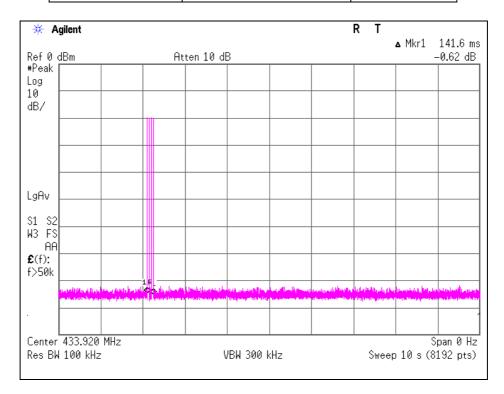
Test place Ise EMC Lab. No.3 Semi Anechoic Chamber

Report No. 11766059H Date 06/02/2017 Temperature/ Humidity 25 deg. C / 42% RH

Engineer Ken Fujita

Normal use mode 433.92 MHz Mode

Time of	Limit	Result
Transmitting		
[sec]	[sec]	
0.1416	5.00	Pass



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Radiated Emission (Electric Field Strength of Fundamental and Spurious Emission) 433.92 MHz

Test place Ise EMC Lab.

Semi Anechoic Chamber No.2 No.3 No.2

Report No. 11766059H

Date 05/27/2017 06/04/2017 08/22/2017

Temperature/ Humidity 23 deg. C / 32% RH 25 deg. C / 42% RH 21 deg. C / 58% RH Engineer Ken Fujita Ken Fujita Shinya Watanabe (Above 1 GHz) (Above 1 GHz) *(Above 1 GHz)*1)

Mode Transmitting mode (Tx), 433.92 MHz

PK

Frequency	Detector	Rea	ding	Ant	Loss	Gain	Duty	Res	sult	Limit	Ma	rgin	Remark
		[dB	uV]	Factor			Factor	[dBu	V/m]		[d	B]	Inside or Outside
[MHz]		Hor	Ver	[dB/m]	[dB]	[dB]	[dB]	Hor	Ver	[dBuV/m]	Hor	Ver	of Restricted Bands
433.920	PK	81.7	82.3	16.4	10.9	32.0	-	77.0	77.6	100.8	23.8	23.2	Carrier
867.840	PK	54.0	53.1	21.7	13.3	31.1	-	57.9	57.0	80.8	22.9	23.8	Outside
1301.760	PK	51.0	51.2	24.9	3.5	35.4	-	44.0	44.2	73.9	29.9	29.7	Inside
1735.680	PK	61.1	59.1	26.6	3.0	35.0	-	55.7	53.7	80.8	25.1	27.1	Outside
2169.600	PK	55.5	52.8	27.2	3.1	34.7	-	51.1	48.4	80.8	29.7	32.4	Outside
2603.520	PK	57.6	54.7	27.2	3.3	34.6	-	53.5	50.6	80.8	27.3	30.2	Outside
3037.440	PK	49.8	48.7	28.0	3.4	34.6	-	46.6	45.5	80.8	34.2	35.3	Outside
3471.360	PK	51.8	51.2	28.4	3.6	34.2	-	49.6	49.0	80.8	31.2	31.8	Outside
3905.280	PK	49.8	48.4	29.4	3.8	33.8	-	49.2	47.8	73.9	24.7	26.1	Inside
4339.200	PK	49.5	50.0	30.3	5.4	33.8	-	51.4	51.9	73.9	22.5	22.0	Inside

Result = Reading + Ant Factor + Loss (Cable+Attenuator+Distance factor(above 1 GHz)) - Gain(Amplifier)

PK with Duty factor

Frequency	Detector	Rea	ding	Ant	Loss	Gain	Duty	Re	sult	Limit	Ma	rgin	Remark
		[dB	uV]	Factor			Factor	[dBu	V/m]		[d	B]	
[MHz]		Hor	Ver	[dB/m]	[dB]	[dB]	[dB]	Hor	Ver	[dBuV/m]	Hor	Ver	
433.920	PK	81.7	82.3	16.4	10.9	32.0	0.0	77.0	77.6	80.8	3.8	3.2	Carrier
867.840	PK	54.0	53.1	21.7	13.3	31.1	0.0	57.9	57.0	60.8	2.9	3.8	Outside
1301.760	PK	51.0	51.2	24.9	3.5	35.4	0.0	44.0	44.2	53.9	9.9	9.7	Inside
1735.680	PK	61.1	59.1	26.6	3.0	35.0	0.0	55.7	53.7	60.8	5.1	7.1	Outside
2169.600	PK	55.5	52.8	27.2	3.1	34.7	0.0	51.1	48.4	60.8	9.7	12.4	Outside
2603.520	PK	57.6	54.7	27.2	3.3	34.6	0.0	53.5	50.6	60.8	7.3	10.2	Outside
3037.440	PK	49.8	48.7	28.0	3.4	34.6	0.0	46.6	45.5	60.8	14.2	15.3	Outside
3471.360	PK	51.8	51.2	28.4	3.6	34.2	0.0	49.6	49.0	60.8	11.2	11.8	Outside
3905.280	PK	49.8	48.4	29.4	3.8	33.8	0.0	49.2	47.8	53.9	4.7	6.1	Inside
4339.200	PK	49.5	50.0	30.3	5.4	33.8	0.0	51.4	51.9	53.9	2.5	2.0	Inside

Result = Reading + Ant Factor + Loss (Cable+Attenuator+Distance factor(above 1 GHz)) - Gain(Amplifier) + Duty factor

Sample calculation:

Result of PK = Reading + Ant Factor + Loss (Cable + Attenuator + Distance factor) - Gain (Amplifier)

Result of PK with Duty factor = Reading + Ant Factor + Loss (Cable + Attenuator + Distance factor) - Gain (Amplifier) + Duty factor

For above 1GHz : Distance Factor: $20 \times \log (4.45 \text{ m}/3.0 \text{ m}) = 3.42 \text{ dB}$

*Other frequency noises omitted in this report were not seen or had enough margin (more than 20dB).

Since the peak emission result satisfied the average limit, duty factor was omitted.

The result of AV (PK with Duty factor) was calculated by applying Duty 100%.

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^{*1)10}th harmonics only

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Radiated Spurious Emission (Plot data, Worst case)

Test place

Semi Anechoic Chamber

Report No.

Date Temperature/ Humidity

Engineer

Mode

Ise EMC Lab.

No.3 No.2

11766059H

05/27/2017 06/04/2017 23 deg. C / 32% RH 25 deg. C / 42% RH

Ken Fujita Ken Fujita (Above 1 GHz) (Below 1 GHz)

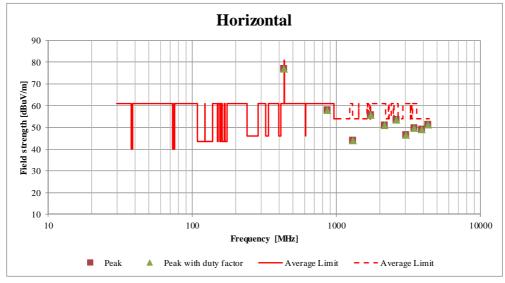
Transmitting mode (Tx), 433.92 MHz

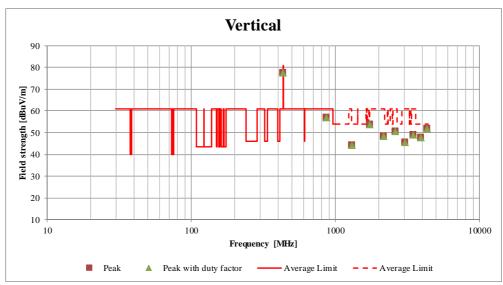
No.2

08/22/2017

21 deg. C / 58% RH Shinya Watanabe (Above 1 GHz) *1)

*1)10th harmonics only





^{*}These plots data contains sufficient number to show the trend of characteristic features for EUT.

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-20dB and 99% Occupied Bandwidth 433.92 MHz

Test place Ise EMC Lab. No.3 Semi Anechoic Chamber

Report No. 11766059H Date 06/03/2017 Temperature/ Humidity 25 deg. C / 42% RH

Engineer Ken Fujita

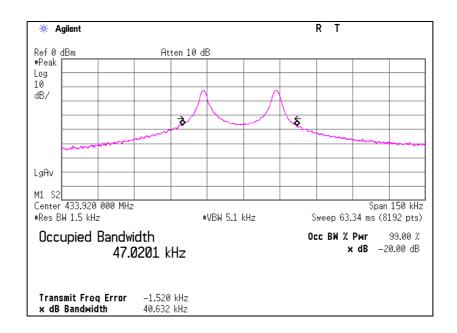
Mode Transmitting mode (Tx), 433.92 MHz

Bandwidth Limit: Fundamental Frequency 433.920 MHz x 0.25% = 1084.80 kHz

* The above limit was calculated from more stringent nominal frequency.

	•	
-20dB Bandwidth	Bandwidth Limit	Result
[kHz]	[kHz]	
40.63	1084.80	Pass

99% Occupied Bandwidth	Bandwidth Limit	Result
[kHz]	[kHz]	
47.02	1084.80	Pass



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APPENDIX 2: Test Instruments

EMI test equipment

Control No.	Instrument	Manufacturer	Model No	Serial No	Test Item	Calibration Date * Interval(month)	
MAEC-02	Semi Anechoic Chamber(NSA)	TDK	Semi Anechoic Chamber 3m	DA-06902	RE	2016/08/02 * 12	
MOS-22	Thermo-Hygrometer	Custom	CTH-201	0003	RE	2016/12/13 * 12	
MJM-14	Measure	KOMELON	KMC-36	-	RE	-	
COTS-MEMI	EMI measurement program	TSJ	TEPTO-DV	-	RE	-	
MSA-03	Spectrum Analyzer	Agilent	E4448A	MY44020357	RE	2017/05/29 * 12	
MHA-06	Horn Antenna 1-18GHz	Schwarzbeck	BBHA9120D	254	RE	2017/02/24 * 12	
MCC-216	Microwave Cable	Junkosha	MWX221	1604S253(1 m) / 1608S087(5 m)	RE	2016/08/29 * 12	
MPA-10	Pre Amplifier	Agilent	8449B 3008A02142		RE	2017/01/16 * 12	
MMM-01	Digital Tester	Fluke	FLUKE 26-3	78030611	RE	2016/08/23 * 12	
MAEC-03	Semi Anechoic Chamber(NSA)	TDK	Semi Anechoic DA-10005 Chamber 3m		RE	2016/10/20 * 12	
MOS-13	Thermo-Hygrometer	Custom	CTH-180	1301	RE	2017/01/20 * 12	
MJM-16	Measure	KOMELON	KMC-36	-	RE	-	
MSA-14	Spectrum Analyzer	Agilent	E4440A	MY48250080	RE	2016/10/14 * 12	
MTR-08	Test Receiver	Rohde & Schwarz	ESCI	100767	RE	2016/09/15 * 12	
MBA-03	Biconical Antenna	Schwarzbeck	BBA9106	1915	RE	2016/10/15 * 12	
MLA-22	Logperiodic Antenna(200-1000MHz)	Schwarzbeck	VUSLP9111B	911B-191	RE	2017/01/26 * 12	
MCC-51	Coaxial cable	UL Japan	-	-	RE	2016/07/26 * 12	
MAT-98	Attenuator	KEYSIGHT	8491A	MY52462349	RE	2016/12/05 * 12	
MPA-13	Pre Amplifier	SONOMA INSTRUMENT	310	260834	RE	2017/03/27 * 12	
MMM-08	DIGITAL HITESTER	Hioki	3805	051201197	RE	2017/01/19 * 12	
MLPA-07	Loop Antenna	UL Japan	-	-	RE	Pre Check	

The expiration date of the calibration is the end of the expired month.

All equipment is calibrated with valid calibrations. Each measurement data is traceable to the national or international standards.

As for some calibrations performed after the tested dates, those test equipment have been controlled by means of an unbroken chains of calibrations.

Test Item:

RE: Radiated emission, 99% Occupied Bandwidth, -20dB bandwidth, and Automatically deactivate tests

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